

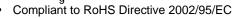
IRF7313TR-VB Datasheet **Dual N-Channel 30-V (D-S) MOSFET**

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A)	Q _g (Typ.)		
30	$0.022 \text{ at V}_{GS} = 10 \text{ V}$	6.8	15 nC		
30	0.026 at V _{GS} = 4.5 V	6.0	10110		

Definition Trench Power MOSFET 100 % UIS Tested 100 % R_g Tested

FEATURES

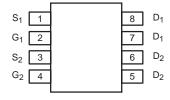
APPLICATIONS Set Top Box Low Current DC/DC



Halogen-free According to IEC 61249-2-21

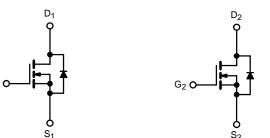


COMPLIANT HALOGEN **FREE**



Top View

SO-8



N-Channel MOSFET

N-Channe	I MOS	SFFT

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted				
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	V
	T _C = 25 °C		6.8 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C] ₋	5.6	
Continuous Diam Current (1) = 100 °C)	T _A = 25 °C	I _D	6.2 ^{b, c}	
	T _A = 70 °C	1	5.2 ^{b, c}	Α
Pulsed Drain Current		I _{DM}	30	^
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	2.25	
Continuous Source-Diam Diode Current	T _A = 25 °C	'5	1.48 ^{b, c}	
Single Pulse Avalanche Current L = 0.1 mH		I _{AS}	5	
Single Pulse Avalanche Energy		E _{AS}	1.25	mJ
	T _C = 25 °C	P _D	2.7	
Maximum Power Dissipation	T _C = 70 °C		1.77	w
Maximum Fower Dissipation	T _A = 25 °C		1.78 ^{b, c}	VV
	T _A = 70 °C		1.14 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 10 s	R _{thJA}	58	70	°C/W	
Maximum Junction-to-Foot (Drain)	-to-Foot (Drain) Steady State		38	45	C/ VV	

Notes:

- a. Package limited, T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 110 °C/W.

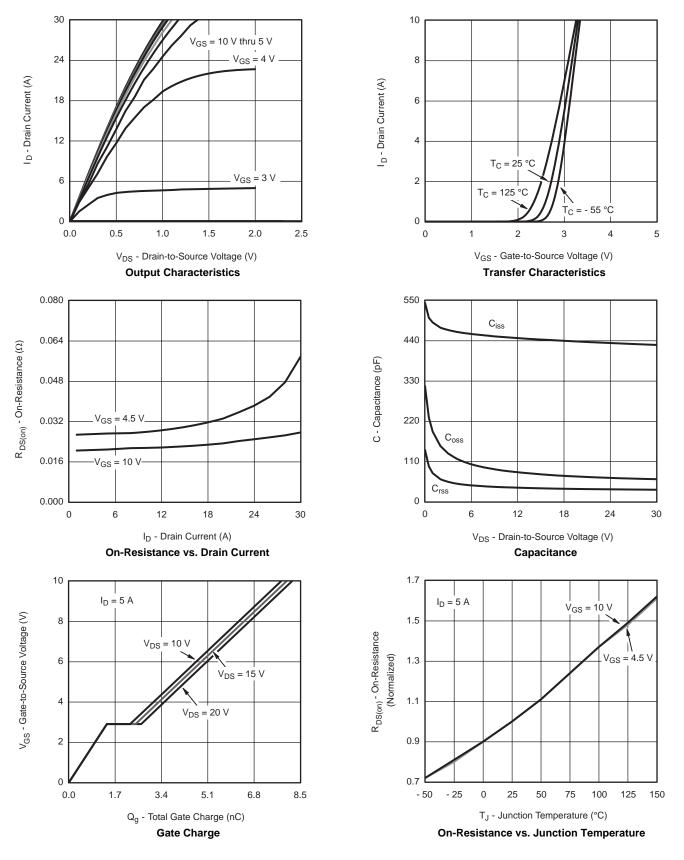


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static			•			•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		32		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.0		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.0		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Oata Valta va Daria Oamani	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α
	5	$V_{GS} = 10 \text{ V, } I_D = 5 \text{ A}$		0.022		1
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4 \text{ A}$		0.026		Ω
Forward Transconductance ^a	g _{fs}	$V_{DS} = 10 \text{ V}, I_D = 5 \text{ A}$		16		S
Dynamic ^b	<u> </u>		1		l	l
Input Capacitance	C _{iss}			586		
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		117		pF
Reverse Transfer Capacitance	C _{rss}			55		
Total Cata Chausa	Qg	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 5 A		15		- nC
Total Gate Charge				3.7	5.6	
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4		
Gate-Drain Charge	Q_{gd}			1.05		
Gate Resistance	R_g	f = 1 MHz	0.8	4.3	8.6	Ω
Turn-On Delay Time	t _{d(on)}			12	24	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 4.5 V, R_g = 1 Ω		11	22	
Fall Time	t _f			8	16	
Turn-On Delay Time	t _{d(on)}			4	8	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 10 V, R_g = 1 Ω		10	20	
Fall Time	t _f			6	12	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.25	۸
Pulse Diode Forward Current	I _{SM}				24	Α
Body Diode Voltage	V_{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L _ E A dl/dt _ 100 A/::2 T _ 25 °C		4	8	nC
Reverse Recovery Fall Time	ta	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		7		
Reverse Recovery Rise Time t _b				4		ns

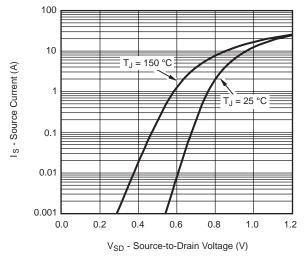
- a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

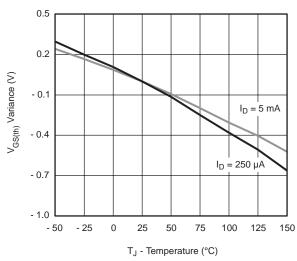




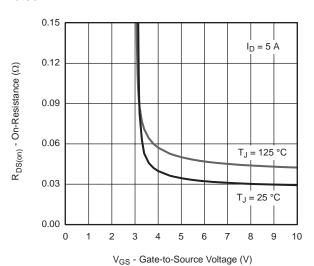




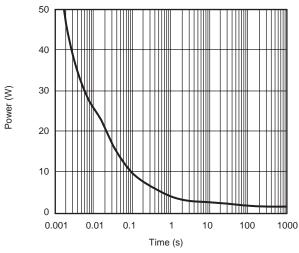
Source-Drain Diode Forward Voltage



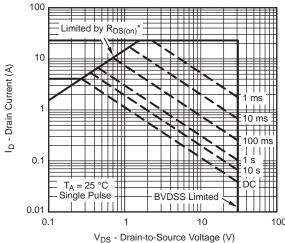
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

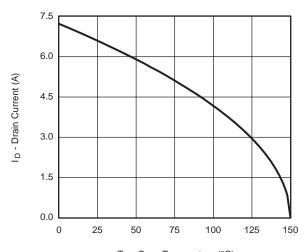


Single Pulse Power



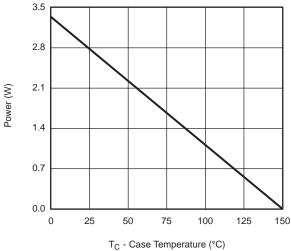
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified Safe Operating Area, Junction-to-Ambient



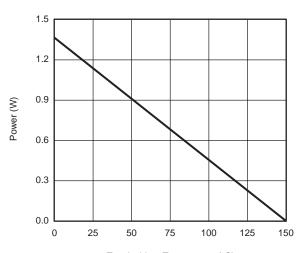


 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*







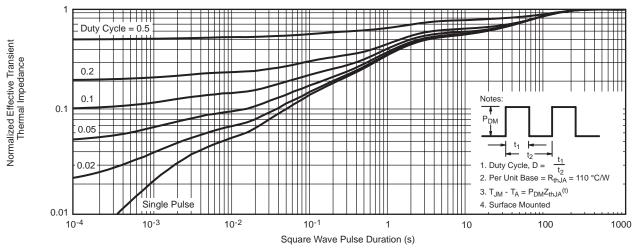
T_A - Ambient Temperature (°C)

Power, Junction-to-Foot

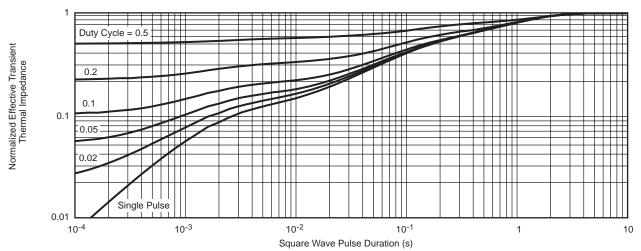
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







	MILLIMETERS		INCHES		
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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